

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L1	1	"6480565".pn.	USPAT	OR	ON	2007/01/18 14:44
L2	4036	382/141,143-152.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:44
L3	940	348/86,87,125,126.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:45
L4	3236	356/237.1,237.4,237.5.ccls.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:49
L5	3589909	wafer semiconductor substrate mask photomask (photo adj mask)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:50
L6	60651	5 near (inspect\$ detect\$ defect)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:52
L7	3666	6 same (killer sensiti\$6 major)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:55
L8	7474	2 3 4	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:56

## EAST Search History

L9	349	7 and 8	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:56
L10	4	7 and (gradation near difference)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 14:57
L11	89	7 and (gradation)	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00
L12	1	(5 and defect and sensitivity and function and parameter and range).clm.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00
L13	7048	hamaguchi.in.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00
L14	39381	nagai.in.	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00
L15	46372	13 14	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00
L16	118	15 and 6	US-PGPUB; USPAT; FPRS; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2007/01/18 15:00

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L17	1	((wafer semiconductor substrate mask photomask (photo adj mask)) and defect and sensitivity and function and parameter and range).clm.	US-PGPUB	OR	ON	2007/01/18 15:01